

RELIABILITY MONITOR

PROCESS: 0.8 μ m Double Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2153Q	A7	DEC.'97	P21120	9730	ANAM-KOREA (AICL)	DN718550AAE	44 PIN PLCC	48	233	0
DS2153Q	A7	MAR '98	P22292	9734	ANAM-KOREA (AICL)	DN720030AAB	44 PIN PLCC	48	237	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2153Q	A7	DEC.'97	P21171	9730	ANAM-KOREA (AICL)	DN718550AAE	44 PIN PLCC	336	77	0
DS2153Q	A7	DEC.'97	P21171	9730	ANAM-KOREA (AICL)	DN718550AAE	44 PIN PLCC	1000	77	0

TOTALS FOR: 0.8 μ m Double Poly, Single Metal FAIL RATE (Fits): 72 DEVICE HRS: 1.28E+07 0

RELIABILITY MONITOR

PROCESS: 0.8 μ m Single Poly, Double Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1302	C1	DEC '97	P21627	9745	ANAM-KOREA (AICL)	DN736077AAC	8 PIN SOIC	48	232	0
DS1302	C1	MAR '98	P21826	9808	HYUNDAI-KOREA (HEI)	DL750312ABA	8 PIN SOIC	48	229	0
DS1315	B1	MAR '98	P21737	9803	ANAM-PI (AAPI)	DK740539AAA	16 PIN PDIP	48	234	0
DS1315	B1	DEC '97	P21188	9737	OMEDATA	DD724444AAC	16 PIN PDIP	48	234	0
DS17485	A2	FEB.'98	P22032	9730	ANAM-KOREA (AICL)	DN713701AAE	24 PIN SOIC	48	230	0
DS17485	A2	NOV. '97	P20961	9726	ANAM-KOREA (AICL)	DN713702AAC	24 PIN SOIC	48	233	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1302	C1	DEC '97	P21731	9745	ANAM-KOREA (AICL)	DN736077AAC	8 PIN SOIC	336	77	0
DS1302	C1	DEC '97	P21731	9745	ANAM-KOREA (AICL)	DN736077AAC	8 PIN SOIC	1000	77	0
DS1302	C1	MAR '98	P21972	9808	HYUNDAI-KOREA (HEI)	DL750312ABA	8 PIN SOIC	336	75	0
DS1302	C1	MAR '98	P21972	9808	HYUNDAI-KOREA (HEI)	DL750312ABA	8 PIN SOIC	1000	75	0
DS1315	B1	MAR '98	P21792	9803	ANAM-PI (AAPI)	DK740539AAA	16 PIN PDIP	336	65	0
DS1315	B1	MAR '98	P21792	9803	ANAM-PI (AAPI)	DK740539AAA	16 PIN PDIP	1000	65	0
DS1315	B1	DEC '97	P21231	9737	OMEDATA	DD724444AAC	16 PIN PDIP	336	77	0
DS1315	B1	DEC '97	P21231	9737	OMEDATA	DD724444AAC	16 PIN PDIP	1000	77	0
DS17485	A2	NOV. '97	P21028	9726	ANAM-KOREA (AICL)	DN713702AAC	24 PIN SOIC	336	77	0
DS17485	A2	NOV. '97	P21028	9726	ANAM-KOREA (AICL)	DN713702AAC	24 PIN SOIC	1000	77	0

RELIABILITY MONITOR

TOTALS FOR: 0.8 μ m Single Poly, Double Metal FAIL RATE (Fits): 8 DEVICE HRS: 1.14E+08 0

RELIABILITY MONITOR

PROCESS: 0.8 µm Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1621	A5	DEC '97	P21367	9740	CARSEM	DM727709AA	8 PIN SOIC	48	236	0
DS1621	A5	MAR '98	P22276	9749	CARSEM	DM705419AB	8 PIN SOIC	48	230	0
DS21S07	E	NOV.'97	P20970	9732	CARSEM	DM717607AB	20 PIN TSSOP	48	232	0
DS21S07	E	FEB '98	P21637	9802	CARSEM	DM741735AB	20 PIN TSSOP	48	234	0
DS2401	B2	MAR '98	P22152	9802	CARSEM	DM741755AC	T0-92	48	234	0
DS2502	B2	DEC.'97	P21290	9743	CARSEM	DM731253AA	8 PIN SOIC	48	234	0
DS80320	B5	JAN '98	P21300	9749	ANAM-PI (AAPI)	DK739467AAA	40 PIN PDIP	48	234	0
DS80320	B5	SEP '97	P20466	9718	ANAM-KOREA (AICL)	DN710449AAB	44 PIN PLCC	48	231	0
DS80320	B5	JUN '97	P19846	9718	ANAM-KOREA (AICL)	DN708196AAX	44 PIN PLCC	48	231	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1621	A5	DEC '97	P21727	9740	CARSEM	DM727709AA	8 PIN SOIC	336	77	0
DS1621	A5	DEC '97	P21727	9740	CARSEM	DM727709AA	8 PIN SOIC	1000	77	0
DS21S07	E	FEB '98	P21694	9802	CARSEM	DM741735AB	20 PIN TSSOP	336	77	0
DS21S07	E	NOV.'97	P21024	9732	CARSEM	DM717607AB	20 PIN TSSOP	336	77	0
DS21S07	E	FEB '98	P21694	9802	CARSEM	DM741735AB	20 PIN TSSOP	1000	77	0
DS21S07	E	NOV.'97	P21024	9732	CARSEM	DM717607AB	20 PIN TSSOP	1000	77	0
DS2401	B2	MAR '98	P22162	9802	CARSEM	DM741755AC	T0-92	336	77	0

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DS2401	B2	MAR '98	P22162	9802	CARSEM	DM741755AC	T0-92	1000	77	0
DS2502	B2	DEC.'97	P21313	9743	CARSEM	DM731253AA	8 PIN SOIC	336	77	0
DS2502	B2	DEC.'97	P21313	9743	CARSEM	DM731253AA	8 PIN SOIC	1000	77	0
DS80320	B5	JAN '98	P21353	9749	ANAM-PI (AAPI)	DK739467AAA	40 PIN PDIP	336	77	0
DS80320	B5	JAN '98	P21353	9749	ANAM-PI (AAPI)	DK739467AAA	40 PIN PDIP	1000	77	0
DS80320	B5	SEP '97	P20546	9718	ANAM-KOREA (AICL)	DN710449AAB	44 PIN PLCC	336	77	1
DS80320	B5	JUN '97	P19923	9718	ANAM-KOREA (AICL)	DN708196AAX	44 PIN PLCC	336	77	0
DS80320	B5	SEP '97	P20546	9718	ANAM-KOREA (AICL)	DN710449AAB	44 PIN PLCC	1000	76	0
DS80320	B5	JUN '97	P19923	9718	ANAM-KOREA (AICL)	DN708196AAX	44 PIN PLCC	1000	77	0

TOTALS FOR: 0.8 μm Single Poly, Single Metal FAIL RATE (Fits): 8 DEVICE HRS: 2.50E+08 1

RELIABILITY MONITOR

PROCESS: 1.2 µm Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1000	E3	FEB '98	P21467	9750	OMEDATA	DD740614ABA	8 PIN PDIP	48	234	0
DS1000	E3	NOV.'97	P20931	9727	OMEDATA	DD711504ABA	8 PIN PDIP	48	234	0
DS1233	A5	OCT '97	P20778	9732	CARSEM	DM721163AC	SOT-223	48	229	0
DS1233	A5	JAN '98	P21396	9737	CARSEM	DM721164AB	SOT-223	48	229	0
DS1267	A1	NOV.'97	P20991	9737	ANAM-PI (AAPI)	DK727730AAA	20 PIN TSSOP	48	234	0
DS1620	C1	MAR '98	P22173	9746	ALPHTK-BANGKOK	DJ723286AAC	8PN SOIC, 208MIL	48	232	0
DS1620	C1	DEC '97	P21529	9740	ALPHTK-BANGKOK	DJ724413AAD	8PN SOIC, 208MIL	48	237	0
DS1669	B3	NOV.'97	P21187	9744	OMEDATA	DD650016AAA	8PN SOIC, 208MIL	48	232	0
DS1669	B3	NOV.'97	P21187	9744	OMEDATA	DD650016AAA	8PN SOIC, 208MIL	48	38	0
DS2401	A2	DEC '97	P21090	9739	CARSEM	DM730233AB	T0-92	48	234	0
DS5002	B3	OCT '97	P20758	9738	CARSEM	DM722224AA	80 PIN PQFP	48	199	0
DS5002F	A3	JAN.'98	P21352	9738	CARSEM	DM720028AA	80 PIN PQFP	48	199	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1000	E3	NOV.'97	P20962	9727	OMEDATA	DD711504ABA	8 PIN PDIP	336	77	0
DS1000	E3	FEB '98	P21488	9750	OMEDATA	DD740614ABA	8 PIN PDIP	336	77	0
DS1000	E3	FEB '98	P21488	9750	OMEDATA	DD740614ABA	8 PIN PDIP	1000	77	0
DS1000	E3	NOV.'97	P20962	9727	OMEDATA	DD711504ABA	8 PIN PDIP	1000	77	0

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DS1233	A5	OCT '97	P20927	9732	CARSEM	DM721163AC	SOT-223	336	77	0
DS1233	A5	JAN '98	P21440	9737	CARSEM	DM721164AB	SOT-223	336	77	0
DS1233	A5	OCT '97	P20927	9732	CARSEM	DM721163AC	SOT-223	1000	77	0
DS1233	A5	JAN '98	P21440	9737	CARSEM	DM721164AB	SOT-223	1000	77	0
DS1267	A1	NOV.'97	P21102	9737	ANAM-PI (AAPI)	DK727730AAA	20 PIN TSSOP	336	77	0
DS1267	A1	NOV.'97	P21102	9737	ANAM-PI (AAPI)	DK727730AAA	20 PIN TSSOP	1000	77	0
DS1620	C1	DEC '97	P21852	9740	ALPHTK-BANGKOK	DJ724413AAD	8PN SOIC, 208MIL	336	77	0
DS1620	C1	DEC '97	P21852	9740	ALPHTK-BANGKOK	DJ724413AAD	8PN SOIC, 208MIL	1000	77	0
DS1669	B3	NOV.'97	P21819	9744	OMEDATA	DD650016AAA	8PN SOIC, 208MIL	336	77	0
DS1669	B3	NOV.'97	P21819	9744	OMEDATA	DD650016AAA	8PN SOIC, 208MIL	1000	76	0
DS2401	A2	DEC '97	P21143	9739	CARSEM	DM730233AB	T0-92	336	77	0
DS2401	A2	DEC '97	P21143	9739	CARSEM	DM730233AB	T0-92	1000	77	0
DS5002	B3	OCT '97	P20837	9738	CARSEM	DM722224AA	80 PIN PQFP	336	77	0
DS5002	B3	OCT '97	P20837	9738	CARSEM	DM722224AA	80 PIN PQFP	1000	77	0

TOTALS FOR: 1.2 µm Single Poly, Single Metal

FAIL RATE (Fits): 3 DEVICE HRS: 2.64E+08 0

RELIABILITY MONITOR

PROCESS: 2.0 µm Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2175S	D1	JAN '98	P21487	9745	ANAM-KOREA (AICL)	DN736121AAE	16 PIN SOIC	48	234	0
DS2180A	B3	NOV.'97	P20995	9734	ANAM-KOREA (AICL)	DN725581AAC	44 PIN PLCC	48	235	0
DS2181	A2	AUG '97	P20303	9728	ANAM-KOREA (AICL)	DN722742ABB	44 PIN PLCC	48	205	0
DS2181A	A2	FEB.'98	P21699	9741	ANAM-KOREA (AICL)	DN728030AAB	44 PIN PLCC	48	237	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2175S	D1	JAN '98	P21612	9745	ANAM-KOREA (AICL)	DN736121AAE	16 PIN SOIC	336	77	0
DS2175S	D1	JAN '98	P21612	9745	ANAM-KOREA (AICL)	DN736121AAE	16 PIN SOIC	1000	77	0
DS2180A	B3	NOV.'97	P21121	9734	ANAM-KOREA (AICL)	DN725581AAC	44 PIN PLCC	336	77	0
DS2180A	B3	NOV.'97	P21121	9734	ANAM-KOREA (AICL)	DN725581AAC	44 PIN PLCC	1000	77	0
DS2181	A2	AUG '97	P20458	9728	ANAM-KOREA (AICL)	DN722742ABB	44 PIN PLCC	336	77	0
DS2181	A2	AUG '97	P20458	9728	ANAM-KOREA (AICL)	DN722742ABB	44 PIN PLCC	1000	77	0
DS2181A	A2	FEB.'98	P21777	9741	ANAM-KOREA (AICL)	DN728030AAB	44 PIN PLCC	336	77	0
DS2181A	A2	FEB.'98	P21777	9741	ANAM-KOREA (AICL)	DN728030AAB	44 PIN PLCC	1000	77	0

TOTALS FOR: 2.0 µm Single Poly, Single Metal FAIL RATE (Fits): 7 DEVICE HRS: 1.23E+08 0

RELIABILITY MONITOR

PROCESS: 3.0 µm Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1210	C1	OCT '97	P20756	9740	HYUNDAI-KOREA (HEI)	DL728002AAC	16 PIN SOIC	48	234	0
DS1210	C1	JAN '98	P21776	9750	HYUNDAI-KOREA (HEI)	DN738347AAA	16 PIN SOIC	48	234	0
DS1232	C1	JAN '98	P21326	9740	HYUNDAI-KOREA (HEI)	DL728793AAF	16 PIN SOIC	48	234	0
DS1232	C1	OCT '97	P20768	9730	HYUNDAI-KOREA (HEI)	DL719711ABD	16 PIN SOIC	48	234	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1210	C1	JAN '98	P22233	9750	HYUNDAI-KOREA (HEI)	DN738347AAA	16 PIN SOIC	336	77	0
DS1210	C1	OCT '97	P20809	9740	HYUNDAI-KOREA (HEI)	DL728002AAC	16 PIN SOIC	336	77	0
DS1210	C1	JAN '98	P22233	9750	HYUNDAI-KOREA (HEI)	DN738347AAA	16 PIN SOIC	1000	77	0
DS1210	C1	OCT '97	P20809	9740	HYUNDAI-KOREA (HEI)	DL728002AAC	16 PIN SOIC	1000	77	0
DS1232	C1	JAN '98	P21403	9740	HYUNDAI-KOREA (HEI)	DL728793AAF	16 PIN SOIC	336	77	0
DS1232	C1	OCT '97	P20817	9730	HYUNDAI-KOREA (HEI)	DL719711ABD	16 PIN SOIC	336	77	0
DS1232	C1	JAN '98	P21403	9740	HYUNDAI-KOREA (HEI)	DL728793AAF	16 PIN SOIC	1000	77	0
DS1232	C1	OCT '97	P20817	9730	HYUNDAI-KOREA (HEI)	DL719711ABD	16 PIN SOIC	1000	77	0

TOTALS FOR: 3.0 µm Single Poly, Single Metal FAIL RATE (Fits): 7 DEVICE HRS: 1.23E+08 0

RELIABILITY MONITOR

PROCESS: 5.0 µm Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2108	B1	NOV.'97	P20993	9735	ANAM-KOREA (AICL)	DN721124AAD	24 PIN SOIC	48	234	0
DS2108	B1	FEB.'98	P21556	9740	ANAM-KOREA (AICL)	DN729120AAC	24 PIN SOIC	48	234	0
DS232	B3	DEC '97	P21091	9742	OMEDATA	DD734647ABF	16 PIN PDIP	48	234	0
DS232	B3	MAR '98	P21726	9809	OMEDATA	DD747723AAB	16 PIN PDIP	48	234	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2108	B1	FEB.'98	P21690	9740	ANAM-KOREA (AICL)	DN729120AAC	24 PIN SOIC	336	77	0
DS2108	B1	NOV.'97	P21077	9735	ANAM-KOREA (AICL)	DN721124AAD	24 PIN SOIC	336	77	0
DS2108	B1	NOV.'97	P21077	9735	ANAM-KOREA (AICL)	DN721124AAD	24 PIN SOIC	1000	77	0
DS2108	B1	FEB.'98	P21690	9740	ANAM-KOREA (AICL)	DN729120AAC	24 PIN SOIC	1000	77	0
DS232	B3	DEC '97	P21152	9742	OMEDATA	DD734647ABF	16 PIN PDIP	336	77	0
DS232	B3	MAR '98	P21751	9809	OMEDATA	DD747723AAB	16 PIN PDIP	336	77	0
DS232	B3	DEC '97	P21152	9742	OMEDATA	DD734647ABF	16 PIN PDIP	1000	77	0
DS232	B3	MAR '98	P21751	9809	OMEDATA	DD747723AAB	16 PIN PDIP	1000	77	0

TOTALS FOR: 5.0 µm Single Poly, Single Metal FAIL RATE (Fits): 11 DEVICE HRS: 8.68E+07 0